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**Przemyslaw Struk
Tadeusz Pustelny**
Editors

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Contents

v	<i>Authors</i>
vii	<i>Conference Committee</i>
ix	<i>Introduction</i>

10455 02	Cross spectral, active, and passive approach to face recognition for improved performance [10455-1]
10455 03	Optical sensor in planar configuration based on multimode interference [10455-2]
10455 04	Modelling of MIR photoluminescence from Pr³⁺ doped chalcogenide fibers pumped at near-infrared wavelengths [10455-3]
10455 05	Dark current simulation in interband cascade photodetectors operating in room temperature [10455-4]
10455 06	Modulators for MWIR detectors with liquid crystals [10455-5]
10455 07	Raman and photoluminescence investigation of InAs/GaSb and InAs/InAsSb superlattices [10455-7]
10455 08	Integrated optical sensor for individual protection of artwork (Invited Paper) [10455-8]
10455 09	Research to improve the accuracy of determining the stroke volume of an artificial ventricle using the wavelet transform [10455-9]
10455 0A	Method of laser beam coding for control systems [10455-10]
10455 0B	The technique of accuracy measurement of membrane shape mapping of an artificial ventricle [10455-11]
10455 0C	Simple thermal to thermal face verification method based on local texture descriptors [10455-12]
10455 0D	Theoretical simulation of the long-wave HgCdTe detector for ultra fast response-operating under zero bias condition and room temperature [10455-13]
10455 0E	Preparation of fluorescent nanodiamond suspensions using bead-assisted ultrasonic disintegration [10455-14]
10455 0F	InAs/GaSb superlattice quality investigation [10455-15]

10455 OG	Optoelectronics technologies for Virtual Reality systems [10455-16]
10455 OH	Modeling of light propagation in canine gingiva [10455-17]
10455 OI	Straight and bended high refractive index rib waveguides: theoretical analysis [10455-18]
10455 OJ	Measurement of luminance and color uniformity of displays using the large-format scanner [10455-19]
10455 OK	ZnO semiconductor for applications in optoelectronics sensors structures (Invited Paper) [10455-21]
10455 OL	Non-invasive assessment of thromboembolism in rotary blood pumps: case study (Invited Paper) [10455-22]
10455 OM	Theoretical analysis of a spectrometric interferometer based on silicon-on insulator (SOI) waveguide layers [10455-74]
10455 ON	Study of the impact of UV radiation on NO₂ sensing properties of graft comb copolymers of poly(3-hexylthiophene) at room temperature [10455-85]
10455 OO	Optoelectronics sensors of hydrocarbons based on NDIR technique [10455-86]
10455 OP	High birefringent microstructured polymer optical fiber with frozen stresses (Invited Paper) [10455-87]
10455 OQ	Stability of thin film diamond mirror for applications in interferometers under the short-time exposure on selected aggressive chemicals [10455-88]
10455 OR	Optical fiber current sensor with external conversion for measurements of low AC electric currents [10455-89]
10455 OS	Detection of optical signals in selected sensing applications (Invited Paper) [10455-90]
10455 OT	Mobility spectrum analysis of HgCdTe epitaxial layers grown by metalorganic chemical vapour deposition [10455-91]
10455 OU	Study of blended conductive graft copolymer with graphite oxide thin films deposited using spin coating method for gas sensing and photovoltaic applications [10455-93]
10455 OV	Experimental determination of leakage current occurring in HgCdTe infrared detectors operating in the mid-infrared [10455-94]
10455 OW	Fiber optic sensor for H₂ gas detection in the presence of methane based on Pd/WO₃ low-coherence interferometric structure [10455-95]
10455 OX	Voltage- and temperature-controlled LC:PDMS waveguide channels (Invited Paper) [10455-96]
10455 OY	Network of photonic sensors for CO₂ exchange rate measurement in forests [10455-98]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Arciuch, Artur, 0A	Mazikowski, Adam, 0J
Asquini, Rita, 0X	Maźniewski, Krzysztof, 0R
Barczak, Kamil, 0R	Mazur, R., 06
Barney, E., 04	Mergo, P., 0P
Benson, T. M., 04	Michalczewski, Krystian, 07, 0F
Benyahia, Djalal, 07, 0F	Mikołajczyk, J., 0S
Beres-Pawlik, E., 04	Morawiak, P., 06
Bieda, Marcin S., 0Y	Mrotek, Marcin, 0H
Bielecki, Z., 0S	Murawska, Monika, 08
Blahut, Marek, 03	Murawski, Krzysztof, 07, 08, 09, 0A, 0B, 0F
Bogdanowicz, Robert, 0E	Pacholewicz, Jerzy, 0L
Boguski, Jacek, 0T	Palka, Norbert, 0C
Budner, Bogusław, 07, 0F	Pałys, Tomasz, 0A
Chodorow, U., 06	Piecek, W., 06
Copik, Izabela, 0L	Piramidowicz, R., 04
Czyżewska, L., 0P	Piszczyk, Marek, 0G
d'Alessandro, Antonio, 0X	Pomianek, Mateusz, 0G
Ficek, Mateusz, 0E	Procek, Marcin, 0N, 0U
Furniss, D., 04	Prokopiuk, Artur, 0O
Gardas, Mateusz, 0E	Pustelny, Tadeusz, 0K
Gawlikowski, Maciej, 0L	Pydziński, Paweł, 0L
Gawron, W., 06	Rutecka, B., 0S
Gil, M., 0P	Rutkowska, Katarzyna A., 0X
Głowacki, Maciej J., 0E, 0L	Rutkowski, Jarosław, 05, 0D, 0V
Gorczyca, Kinga, 0T	Sakr, H., 04
Grad, Leszek, 09, 0B	Sawczak, Mirosław, 0E
Grodecki, Kacper, 07, 0F	Seddon, A. B., 04
Grudzien, A., 02, 0C	Sobotka, Piotr, 0Y
Gut, Kazimierz, 0M	Sojka, L., 04
Hackiewicz, K., 05	Stolarczyk, Agnieszka, 0N, 0U
Henig, Aleksandra, 07, 0F	Struk, Przemysław, 0K
Herman, J., 06	Sujecki, S., 04
Hirsch, M., 0Q	Sulej, Wojciech, 09, 0B
Jankiewicz, Bartłomiej, 07, 0F	Szabra, D., 0S
Kałużński, P., 0U	Szustakowski, Mieczysław, 02, 0G
Kębtowski, Artur, 0T	Tang, Z., 04
Kłos, K., 0S	Tyszkiewicz, Cuma, 0I
Kopytko, Małgorzata, 0V	Umana-Membreno, Gilberto A., 0T
Kowalewski, Andrzej, 05, 06, 0V	Walczak, Andrzej, 0A
Kowalski, M., 02, 0C	Wójcik, G., 0P
Kubacki, Krzysztof, 0L	Wojtas, J., 0S
Kubiszyn, Łukasz, 07, 0F	Woliński, Tomasz R., 0Y
Kula, P., 06	Wróbel, Jarosław, 0T
Kustosz, Roman, 0L	Wysmolek, A., 07
Lesiak, Piotr, 0Y	Zakliczyński, Michał, 0L
Maciak, Erwin, 0N, 0U, 0W	
Maciejewski, Marcin, 0G	
Madejczyk, Paweł, 0D, 0T	
Majchrowicz, D., 0Q	
Markowska, Olga, 0V	
Martyniuk, Piotr, 05, 06, 07, 0D, 0F, 0T, 0V	

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Introduction

The Conference on INTEGRATED OPTICS: Sensors, Sensing Structures and Methods is an international scientific forum of photonics and modern nanotechnology.

The Integrated Optics (IOS) conference is organized every year since 2004 and in 2017 it was held for the twelfth time.

IOS'2017 took place from February 27 to March 3, 2017 in Szczyrk, in the META Hotel, in the Beskidy Mountains in southern Poland, a real winter scenery. IOS'2017 was attended by 60 scientists, mainly from Poland, as well as from Australia, Qatar and Slovakia.

The main organizer of the 12th IOS'2017 was the Photonics Society of Poland in cooperation with SPIE. The technical co-organizers of the conference were: the Upper Silesian Division of the Polish Acoustical Society and the Optoelectronic Department at the Silesian University of Technology in Gliwice (Poland).

The Honorary patronage of the Conference has taken over by Professor Wiesław Wołoski – Full Member of the Polish Academy of Sciences.

During the IOS'2017 conference thirty-eight oral lectures were held in 8 scientific sessions. In addition, twenty one posters were presented during the poster session.

The main aim of the Conference was an exchange of knowledge in the scope of practical applications of photonics, integrated optics and related scientific areas. The objectives of the Conference were also presentations of experiences in the field of technology and theoretical analysis of optoelectronic sensors and practical applications of sensing structures and systems, as well as new methods in the field of modern metrology.

The IOS'2017 Conference has contributed to the extension of relations between scientific groups and has enabled the intensification of common cooperation for the development of photonics and integrated optics.

Tadeusz Pustelny